

Search Notes**Application/Control No.**

10/538,715

Examiner

Taeyoon Kim

**Applicant(s)/Patent under
Reexamination**

FARDEAU ET AL.

Art Unit

1651

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search	5/12/2009	TK